

<b>Notice of References Cited</b>	Application/Control No. 10/605,481		Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,521,948 B2	02-2003	Ebina, Akihiko	257/347
	B	US-6,734,500 B2	05-2004	Ebina, Akihiko	257/347
	C	US-5,821,575 A	10-1998	Mistry et al.	257/281
	D	US-6,657,257 B2	12-2003	Ohyanagi et al.	257/347
	E	US-5,973,364 A	10-1999	Kawanaka, Shigeru	257/347
	F	US-5,920,093 A	07-1999	Huang et al.	257/347
	G	US-6,693,326 B2	02-2004	Adan, Alberto O.	257/347
	H	US-5,844,272 A	12-1998	Soderbarg et al.	257/328
	I	US-6,642,579 B2	11-2003	Fung, Ka Hing	257/347
	J	US-6,404,015 B2	06-2002	Emmerik et al.	257/348
	K	US-6,191,449 B1	02-2001	Shino, Tomoaki	257/347
	L	US-6,353,245 B1	03-2002	Unnikrishnan, Sreenath	257/347
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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